AEDX-8xxx-xxx
2- and 3-Channel Incremental Optical Kit Encoder

Avago
T E C H N O L O G I E S

Reliability Data Sheet

Description

The following cumulative test results have been obtained from testing performed at Avago Technologies Malaysia in accordance to IEC standard. Avago tests parts at the absolute maximum characteristics of your rated conditions recommended for the device. The actual performance you obtain from Avago parts, depend on the electrical and environmental application but will probably be better than the performance outlined in Table 1.

Table 1. Life Tests

Test Name	Reference	Test Conditions	Units Tested	Unit Failed
Dry Heat	IEC680068-2-2	Stored in TA= 100°C for 168 hours with charge voltage Vcc=5.5V and measured in room temperature	40	0
Cold Test	IEC680068-2-1	Stored in TA= - 40°C for 168 hours with charge voltage Vcc=5.5V and measured in room temperature	33	0
Damp Heat Steady State	IEC60068-2-3	Stored in TA = 85°C, RH = 85% for 336 hours with charge voltage Vcc=5.5V and measured in room temperature	40	0

Table 2. Environmental Tests

Test Name	Reference	Test Conditions	Units Tested	Unit Failed
Change of Temperature	IEC60068-2-14Nb	-40°C to 100°C, 30min dwell time. Ramp rate: 3°C/ min. After 100 cycles, measured in room temperature	40	0

Table 3. Electrical Tests

Test Name	Reference	Test Conditions	Units Tested	Unit Failed
Electrostatic Discharge Immunity Test	IEC61000-4-2	Charged at 8Kv at 10 pulses each and measured at room temperature	3	0

Table 4. Mechanical Tests

Test Name	Reference	Test Conditions	Units Tested	Unit Failed
Mechanical Shock Test (non-operating)	IEC68-2-27	50G at 11msec. 5 successive shocks in each direction of 3 perpendicular axes of units. Measured in room temperature	3	0
Vibration Test	IEC68-2-6	20Hz to 2000Hz at 30G, 15min per axes 10 cycles per 3 perpendicular axes of units	3	0

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